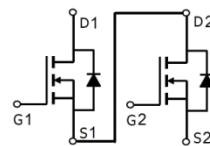


NIKO-SEM
**Dual N-Channel Enhancement Mode
Field Effect Transistor**
PK650DY
PDFN 5x6P
Halogen-Free & Lead-Free
PRODUCT SUMMARY

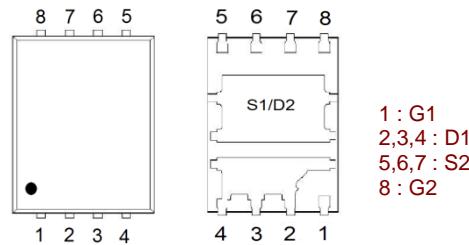
	$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
Q2	30V	2.8mΩ	83A
Q1	30V	11mΩ	36A

**Features**

- Pb-Free, Halogen Free and RoHS compliant.
- Low $R_{DS(on)}$ to Minimize Conduction Losses.
- Ohmic Region Good $R_{DS(on)}$ Ratio.
- Optimized Gate Charge to Minimize Switching Losses.

Applications

- Protection Circuits Applications.
- Logic/Load Switch Circuits Applications
- Computer for DC to DC Converters Applications.

**ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	Q2	Q1	UNITS
Drain-Source Voltage	V_{DS}	30	30	V
Gate-Source Voltage	V_{GS}	± 20	± 20	V
Continuous Drain Current ³	$I_C = 25^\circ\text{C}$	I_D	83	36
	$T_C = 100^\circ\text{C}$		52	23
Pulsed Drain Current ¹	I_{DM}	130	55	A
Continuous Drain Current	$T_A = 25^\circ\text{C}$	I_D	21	
	$T_A = 70^\circ\text{C}$		17	
Avalanche Current	I_{AS}	52	21	
Avalanche Energy	E_{AS}	135	22	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	36	28
	$T_C = 100^\circ\text{C}$		14	11
Power Dissipation	$T_A = 25^\circ\text{C}$	P_D	2.4	2
	$T_A = 70^\circ\text{C}$		1.5	1.3
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150		°C

NIKO-SEM**Dual N-Channel Enhancement Mode
Field Effect Transistor****PK650DY
PDFN 5x6P
Halogen-Free & Lead-Free****THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL		TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	R _{θJA}	Q2		51	°C / W
	R _{θJA}	Q1		60	
Junction-to-Case	R _{θJC}	Q2		3.4	°C / W
	R _{θJC}	Q1		4.4	

¹Pulse width limited by maximum junction temperature T_{J(MAX)}=150°C.²The value of R_{θJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The value in any given application depends on the user's specific board design.³Package limitation current :Q1=29A,Q2=42A.**ELECTRICAL CHARACTERISTICS (T_J = 25 °C, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D = 250μA	Q2	30		V
			Q1	30		
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250μA	Q2	1.3	1.75	2.3
			Q1	1.3	1.75	2.3
Gate-Body Leakage	I _{GSS}	V _{DS} = 0V, V _{GS} = ±20V	Q2			±100
			Q1			±100
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 24V, V _{GS} = 0V	Q2			1
			Q1			1
		V _{DS} = 20V, V _{GS} = 0V, T _J = 55 °C	Q2			10
			Q1			10
Drain-Source On-State Resistance ¹	R _{DS(ON)}	V _{GS} = 4.5V, I _D = 16A	Q2		2.1	3.8
		V _{GS} = 4.5V, I _D = 10A	Q1		10	14
		V _{GS} = 10V, I _D = 20A	Q2		1.6	2.8
		V _{GS} = 10V, I _D = 10A	Q1		6.8	11
Forward Transconductance ¹	g _{fs}	V _{DS} = 5V, I _D = 20A	Q2		55	
		V _{DS} = 5V, I _D = 10A	Q1		40	

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DYNAMIC							
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 15V, f = 1MHz$	Q2		3685		pF
Output Capacitance	C_{oss}		Q1		531		
Reverse Transfer Capacitance	C_{rss}		Q2		615		
Gate Resistance	R_g		Q1		147		
Total Gate Charge ²	Q_g		Q2		388		
Gate-Source Charge ²	Q_{gs}		Q1		67		
Gate-Drain Charge ²	Q_{gd}	$V_{GS} = 10V$ Q2 $V_{DS} = 15V, I_D = 20A$ Q1 $V_{DS} = 15V, I_D = 10A$	Q2		1		Ω
Turn-On Delay Time ²	$t_{d(on)}$		Q1		1		
Rise Time ²	t_r		Q2		72		
Turn-Off Delay Time ²	$t_{d(off)}$		Q1		10		
Fall Time ²	t_f		Q2		37		
Continuous Current ³	I_s		Q1		5.6		
Forward Voltage ¹	V_{SD}		Q2		10		
Reverse Recovery Time	t_{rr}		Q1		1.4		
Reverse Recovery Charge	Q_{rr}		Q2		18		
			Q1		3		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)							
Continuous Current ³	I_s	$I_F = 20A, V_{GS} = 0V$	Q2			36	A
Forward Voltage ¹	V_{SD}		Q1			23	
Reverse Recovery Time	t_{rr}	$I_F = 10A, V_{GS} = 0V$	Q2			1	V
Reverse Recovery Charge	Q_{rr}	$I_F = 20A, dI_F/dt = 100A/\mu S$	Q1			1.2	
		$Q2$ $I_F = 20A, dI_F/dt = 100A/\mu S$	Q2		28		nS
		$Q1$ $I_F = 10A, dI_F/dt = 100A/\mu S$	Q1		8.8		
		$Q2$ $I_F = 10A, dI_F/dt = 100A/\mu S$	Q2		13		nC
		$Q1$ $I_F = 10A, dI_F/dt = 100A/\mu S$	Q1		1.2		

¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Package limitation current : Q1=29A, Q2=42A.

NIKO-SEM

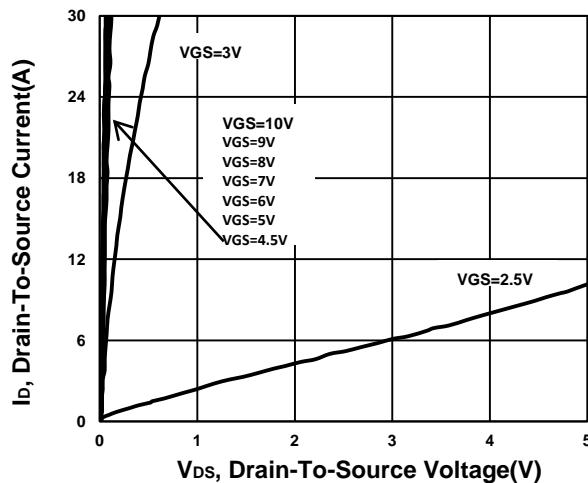
**Dual N-Channel Enhancement Mode
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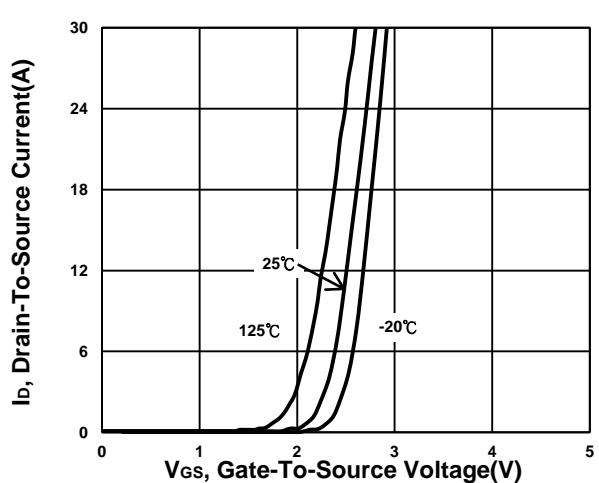
TYPICAL PERFORMANCE CHARACTERISTICS

Q2

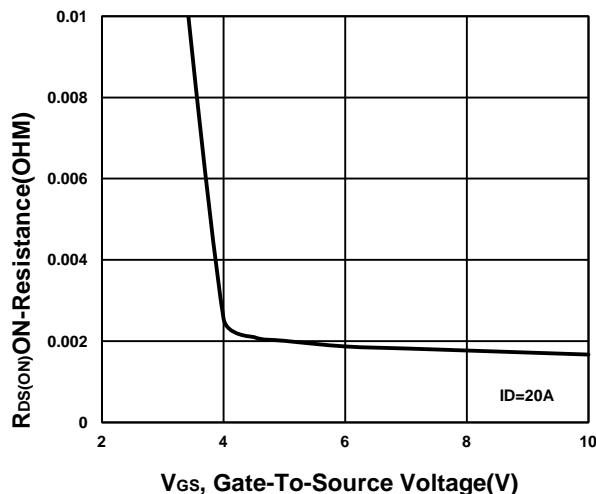
Output Characteristics



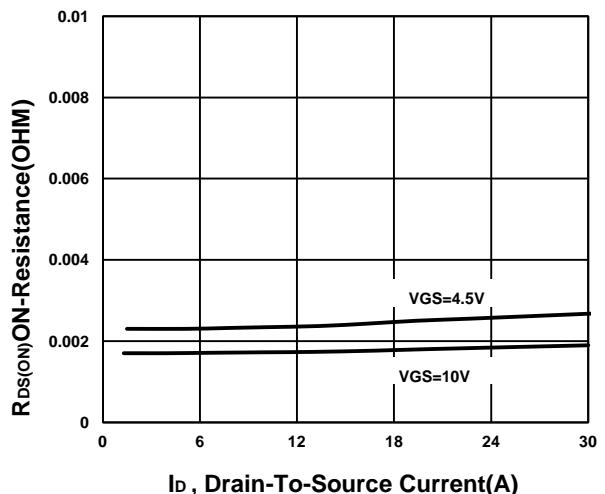
Transfer Characteristics



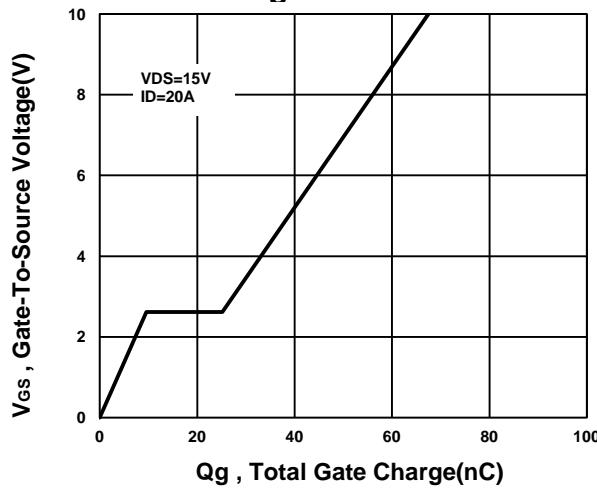
On-Resistance VS Gate-To-Source



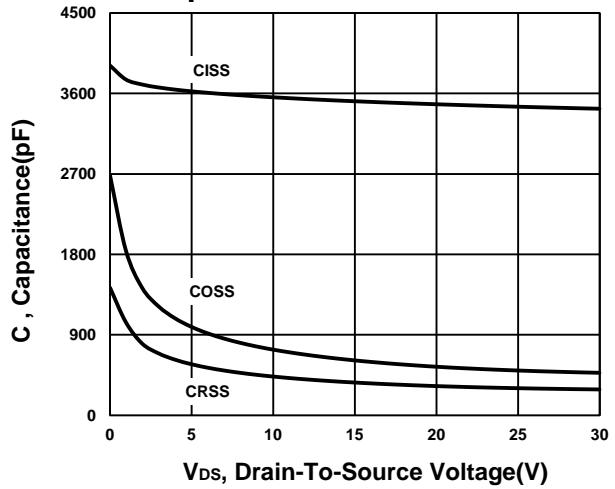
On-Resistance VS Drain Current

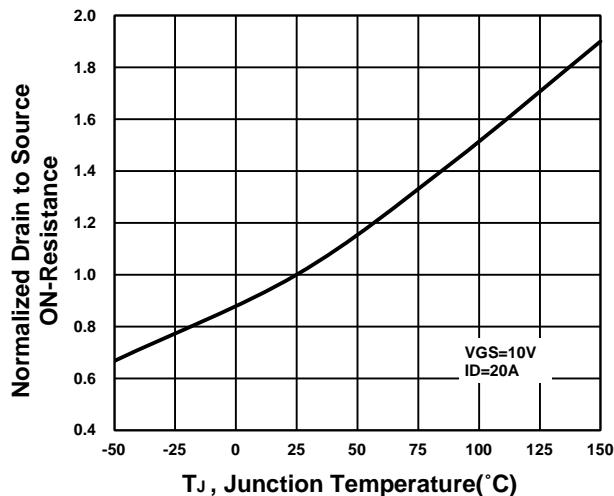
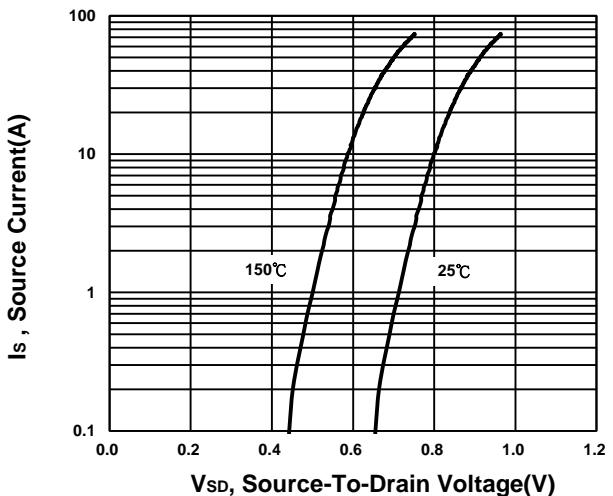
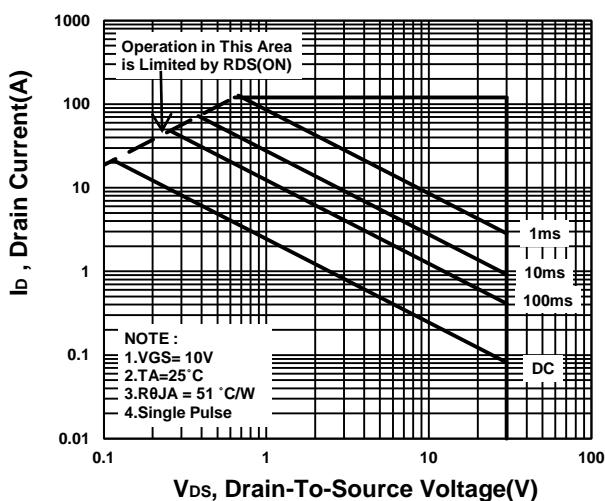
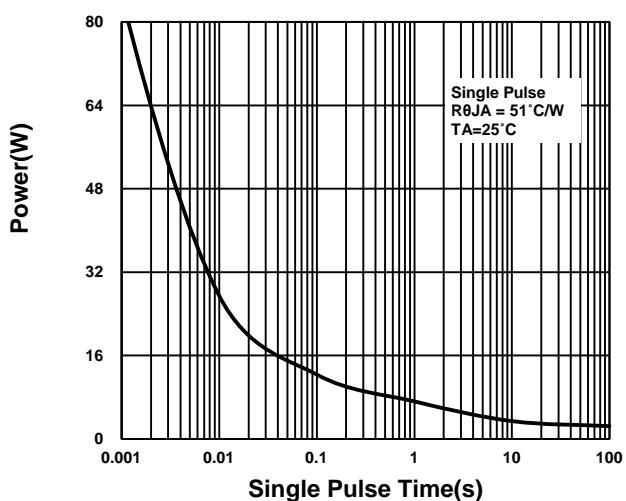
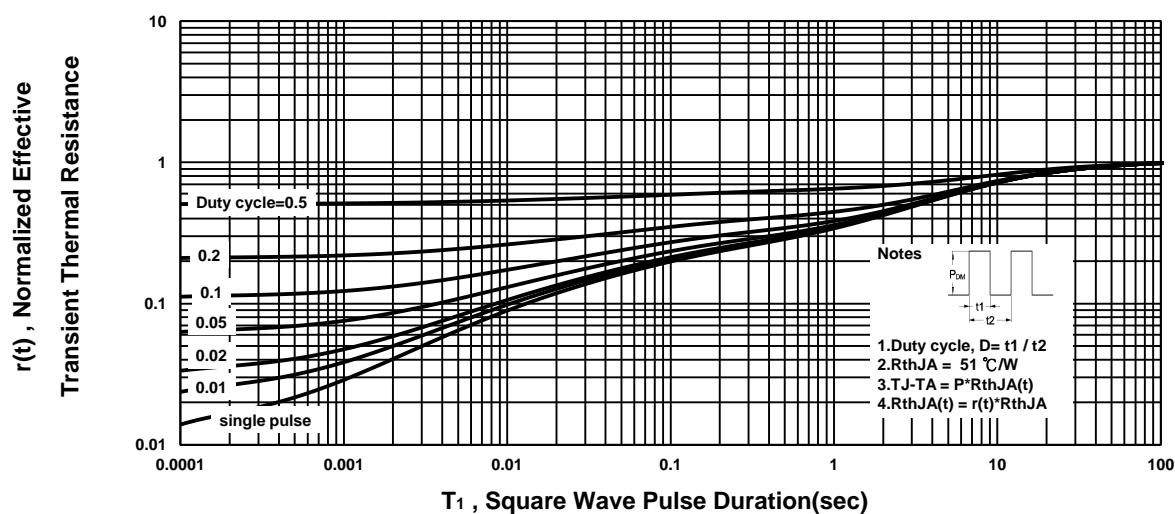


Gate charge Characteristics



Capacitance Characteristic



NIKO-SEM**Dual N-Channel Enhancement Mode
Field Effect Transistor****PK650DY**
PDFN 5x6P
Halogen-Free & Lead-Free**On-Resistance VS Temperature****Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**

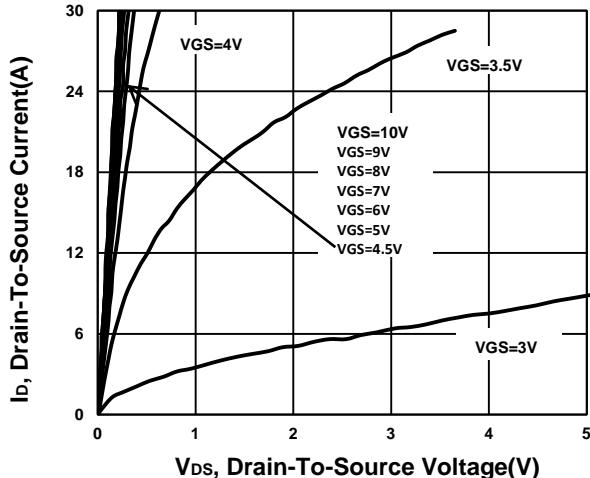
NIKO-SEM

**Dual N-Channel Enhancement Mode
Field Effect Transistor**

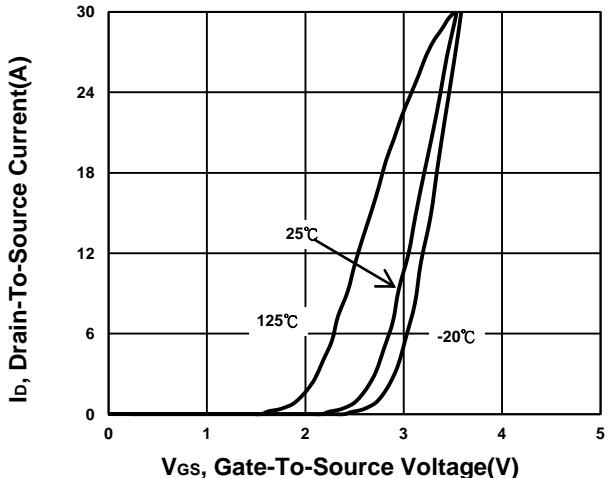
PK650DY
PDFN 5x6P
Halogen-Free & Lead-Free

Q1

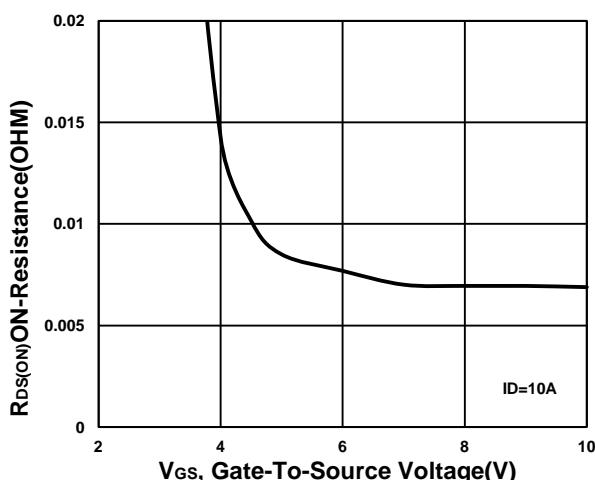
Output Characteristics



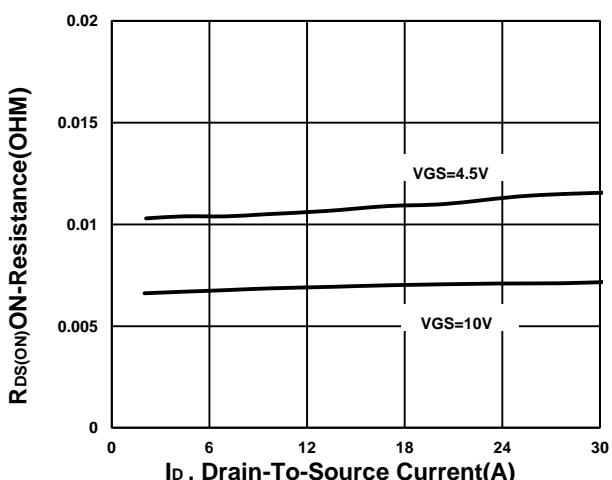
Transfer Characteristics



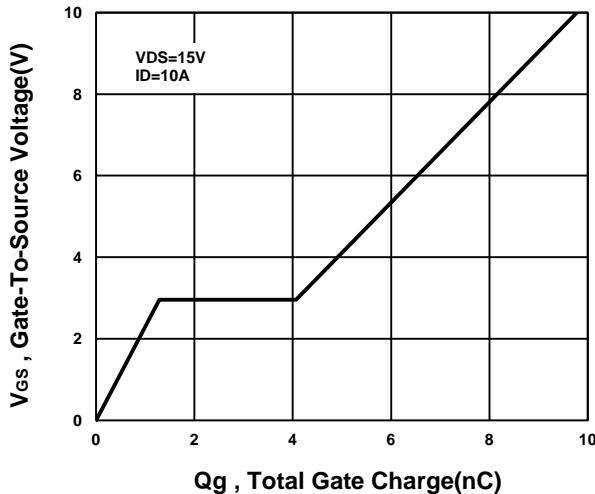
On-Resistance VS Gate-To-Source



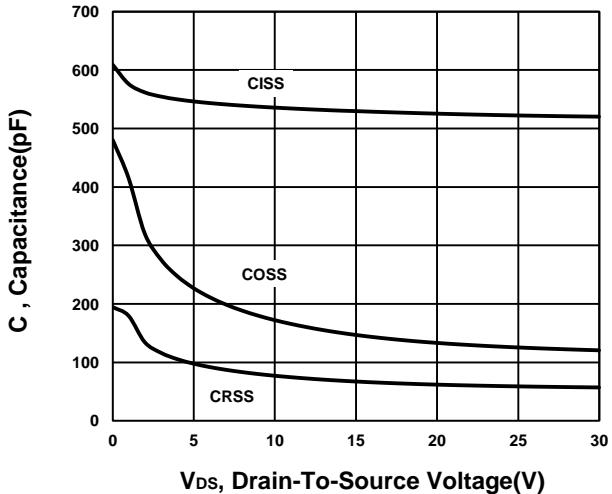
On-Resistance VS Drain Current



Gate charge Characteristics



Capacitance Characteristic



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